

Amendment to the Claims:

This listing of claims will replace all prior versions, and listings, of claims in the application:

Listing of Claims:

Claims 1-57 (Canceled)

Claim 58 (Previously amended): A test apparatus for testing an electronic device, said test apparatus comprising:

 a contactor comprising a first plurality of terminals;

 an interposer comprising:

 a substrate,

 a first plurality of elongate, resilient contact elements extending from a first side of said substrate, and

 a second plurality of contact elements corresponding to a second side of said substrate, ones of said first plurality of contact elements being electrically connected to ones of said second plurality of contact elements; and

 means for attaching said interposer to said contactor such that at least one of said contactor or said interposer is moveable between a first position and a second position while said interposer is attached to said contactor, wherein in said first position, said first plurality of contact elements do not contact said first terminals on said contactor, and in said second position, said first plurality of contact elements contact said first terminals on said contactor and said first plurality of contact elements and said second plurality of contact elements provide electrical connections from said first terminals on said contactor to a second plurality of terminals on said electronic device.

Claim 59 (Canceled)

Claim 60 (Previously presented): The test apparatus of claim 58, wherein each of said contact elements of at least one of said first plurality of contact elements and said second plurality of contact elements are lithographically formed.

Claim 61 (Previously presented): The test apparatus of claim 58, wherein each of said contact elements of at least one of said first plurality of contact elements and said second plurality of contact elements comprise a cantilever beam.

Claim 62 (Previously presented): The test apparatus of claim 76, wherein said first plurality of contact elements are disposed on said first side of said substrate at a first pitch, and said second plurality of contact elements are disposed on said second side of said substrate at a second pitch different than said first pitch.

Claim 63 (Previously presented): The test apparatus of claim 58, wherein said substrate is flexible.

Claim 64 (Previously presented): The test apparatus of claim 58, wherein said substrate comprises silicon.

Claim 65 (Previously presented): The test apparatus of claim 58 further comprising an electronic component disposed on said substrate.

Claim 66 (Previously presented): The test apparatus of claim 65, wherein said electronic component is disposed between ones of said contact elements.

Claim 67 (Previously presented): The test apparatus of claim 65 further comprising a plurality of said electronic components.

Claim 68 (Previously presented): The test apparatus of claim 67, wherein at least one of said plurality of electronic components is disposed on said first side of said substrate between ones of said first plurality of contact elements, and at least another of said plurality of electronic components is disposed on said second side of said substrate between ones of said second plurality of contact elements.

Claim 69 (Previously presented): The test apparatus of claim 58, wherein said first plurality of contact elements are compressed while said ones of said second plurality of terminals on said electronic device are pressed against said ones of said second plurality of contact elements.

Claim 70 (Previously presented): The test apparatus of claim 69 further comprising a stop structure for limiting compression of said first plurality of contact elements.

Claim 71 (Previously presented): The test apparatus of claim 58, wherein said contactor comprises an integrated circuit.

Claim 72 (Previously presented): The test apparatus of claim 71, wherein said contactor comprises a plurality of integrated circuits.

Claim 73 (Previously presented): The test apparatus of claim 71, wherein said first plurality of terminals are disposed on said integrated circuit.

Claim 74 (Previously presented): The test apparatus of claim 71, wherein said integrated circuit comprises circuitry for testing said electronic device.

Claim 75 (Canceled)

Claim 76 (Previously presented): The apparatus of claim 58, wherein said first plurality of elongate, resilient contact elements is disposed on said first side of said substrate, and said second plurality of contact elements is disposed on said second side of said substrate.

Claim 77 (Previously presented): The apparatus of claim 58, wherein said contactor further comprises an interface to a host controller.

Claim 78 (Previously presented): The apparatus of claim 83, wherein said base is further configured to move said electronic device such that said ones of said second plurality of terminals on said electronic device are moved out of contact with said ones of said second plurality of contact elements.

Claims 79 and 80 (Canceled)

Claim 81 (Previously presented): The apparatus of claim 58, wherein said electronic device comprises a semiconductor device.

Claim 82 (Canceled)

Claim 83 (Previously presented): The apparatus of claim 58 further comprising a base for supporting said electronic device.

Claim 84-92 (Canceled)

Claim 93 (Currently amended): A The test apparatus of claim 58 for testing an electronic device, said test apparatus comprising:

a contactor comprising a first plurality of terminals;

an interposer comprising:

a substrate,

a first plurality of elongate, resilient contact elements extending from a first side of said substrate, and

a second plurality of contact elements corresponding to a second side of said substrate, ones of said first plurality of contact elements being electrically connected to ones of said second plurality of contact elements; and

means for attaching said interposer to said contactor such that at least one of said contactor or said interposer is moveable between a first position and a second position while said interposer is attached to said contactor,

wherein in said first position, said first plurality of contact elements do not contact said first terminals on said contactor, and

in said second position, said first plurality of contact elements contact said first terminals on said contactor and said first plurality of contact elements and said second plurality of contact elements provide electrical connections from said first terminals on said contactor to a second plurality of terminals on said electronic device, wherein said means for attaching further allows, while said interposer is attached to said contactor, said interposer ~~can be moved to move~~ from said first position to said second position [[by]] upon application of forces to ones of said second plurality of contact elements.

Claim 94 (Currently amended): The test apparatus of claim 93, wherein said means for attaching further functions to allow, while said interposer is attached to said contactor, said interposer to move from said second position to said first position upon removal of said forces from said second plurality of contact elements results in said interposer moving from said second position to said first position.

Claim 95 (Currently amended): A The test apparatus of claim 58 for testing an electronic device, said test apparatus comprising:

a contactor comprising a first plurality of terminals;

an interposer comprising:

a substrate,

a first plurality of elongate, resilient contact elements extending from a first side of said substrate, and

a second plurality of contact elements corresponding to a second side of said substrate, ones of said first plurality of contact elements being electrically connected to ones of said second plurality of contact elements; and

means for attaching said interposer to said contactor such that at least one of said contactor or said interposer is moveable between a first position and a second position while said interposer is attached to said contactor,

wherein in said first position, said first plurality of contact elements do not contact said first terminals on said contactor, and
in said second position, said first plurality of contact elements contact said first terminals on said contactor and said first plurality of contact elements and said second plurality of contact elements provide electrical connections from said first terminals on said contactor to a second plurality of terminals on said electronic device, wherein said means for attaching further allows, while said interposer is attached to said contactor, said interposer can be moved to move from said first position to said second position by pressing in response to ones of said second plurality of terminals on said electronic device being pressed against [[said]] ones of said second plurality of contact elements.

Claim 96 (Previously presented): The test apparatus of claim 58, wherein said substrate is a single block structure.

Claim 97 (Previously presented): The test apparatus of claim 96, wherein said first contact elements are attached to and extend from said first side of said block structure, and said second contact elements are attached to and extend from said second side of said block structure.

Claim 98-100 (Canceled)

Claim 101 (New): The test apparatus of claim 58, wherein the contactor comprises an integrated circuit and ones of the first plurality of terminals are input pads or output pads of the integrated circuit.

Claim 102 (New): The test apparatus of claim 101, wherein the integrated circuit comprises power regulator circuitry configured to regulate power provided to said electronic device.

Claim 103 (New): The test apparatus of claim 101, wherein the integrated circuit comprises power regulator circuitry configured to output to one of the output pads regulated power.